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**Komori et al.**

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(54) **SOLAR CELL ELEMENT AND METHOD FOR MANUFACTURING SAME**

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**H01L 31/0224** (2006.01)  
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(Continued)

(58) **Field of Classification Search**  
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See application file for complete search history.

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*Primary Examiner* — Jonathan Johnson

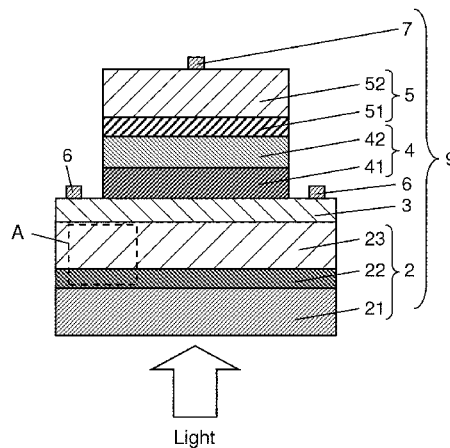
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(57) **ABSTRACT**

A solar cell element having a transparent substrate body, a  $\text{Na}_x\text{Ag}_{1-x}$  layer, a ZnO layer, a transparent conductive layer, and a photoelectric conversion layer including an n-type semiconductor layer and a p-type semiconductor layer. The transparent substrate body, the  $\text{Na}_x\text{Ag}_{1-x}$  layer, the ZnO layer, the transparent conductive layer, and the photoelectric conversion layer are stacked in this order, x represents a value of not less than 0.001 and not more than 0.02, the  $\text{Na}_x\text{Ag}_{1-x}$  layer has a thickness of 2-15.2 nanometers, and the ZnO layer has an arithmetical mean roughness of not less than 20-750 nanometers. The ZnO layer is composed of a plurality of ZnO columnar crystal grain, each ZnO columnar crystal grain has a longitudinal direction along a normal line direction of the transparent substrate body, and each ZnO columnar crystal grain has a R2/R1 ratio of 1.1-1.6.

**15 Claims, 9 Drawing Sheets**



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*H01L 31/0216* (2014.01) 2014/0124032 A1 \* 5/2014 Komori et al. .... 136/256  
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*H01L 31/0392* (2006.01) FOREIGN PATENT DOCUMENTS

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(2013.01); *H01L 31/02366* (2013.01); *H01L* JP 2011-176283 A 9/2011  
*31/0392* (2013.01); *H01L 31/03921* (2013.01) WO WO2012014572 A1 \* 2/2012 ..... H01L 31/04

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FIG. 1

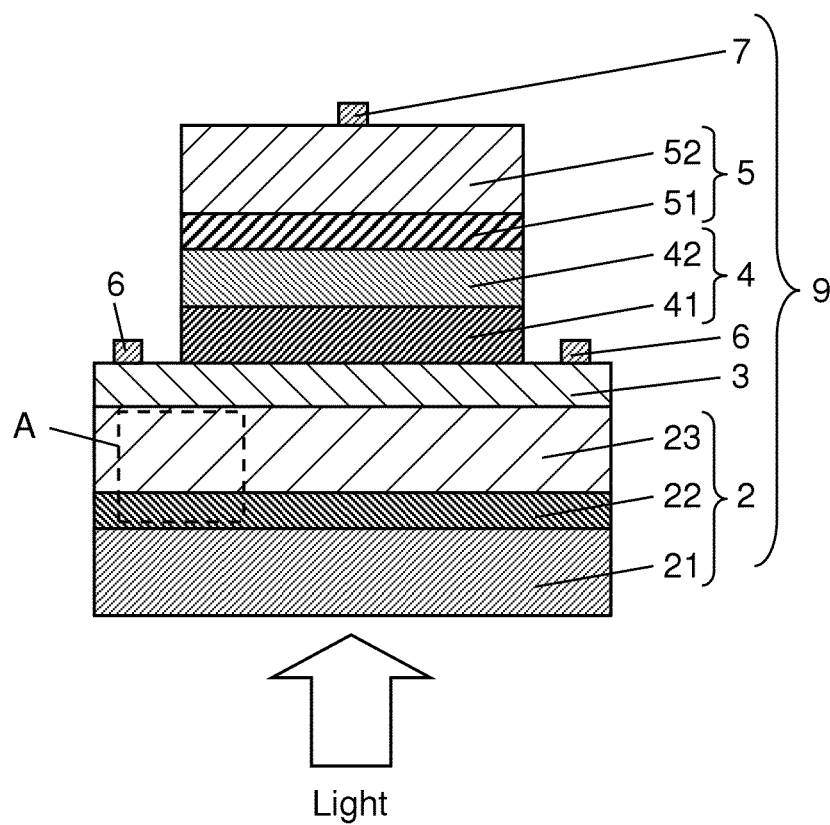


FIG. 2

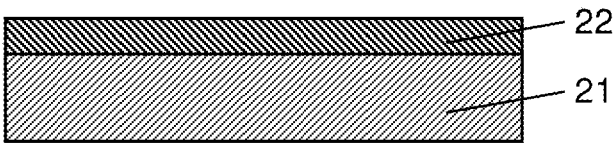


FIG. 3

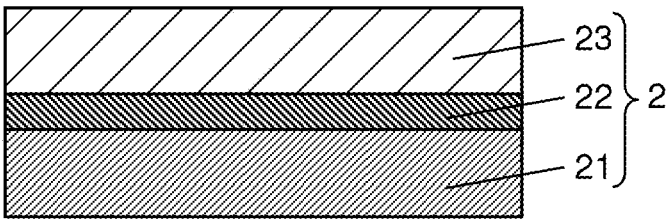


FIG. 4

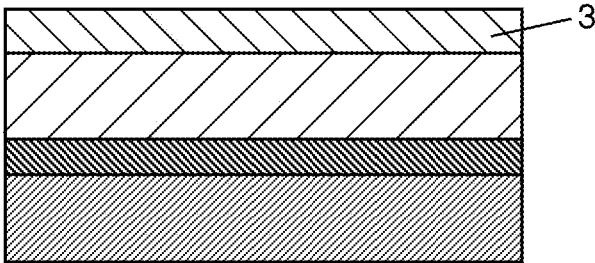


FIG. 5

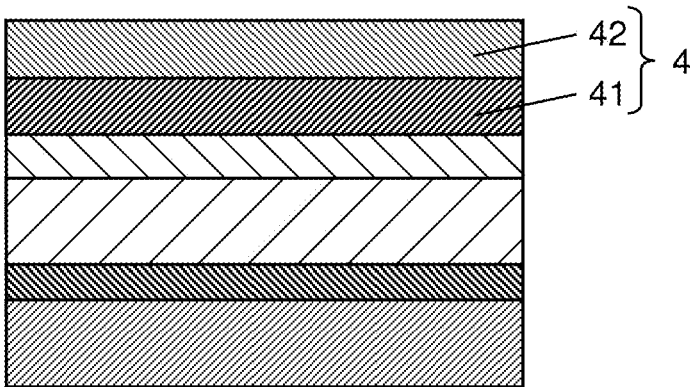


FIG. 6

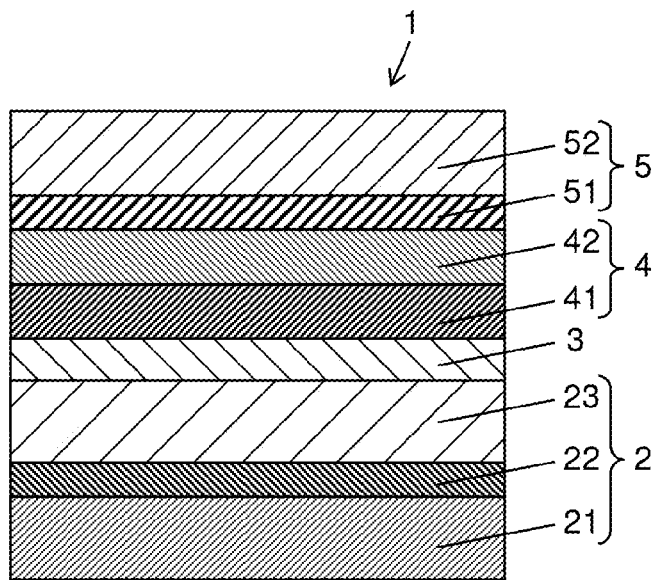


FIG. 7

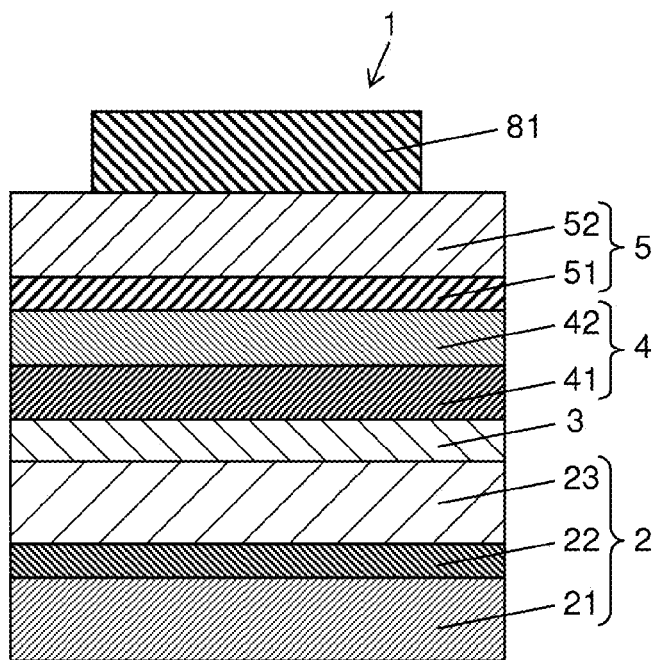


FIG. 8

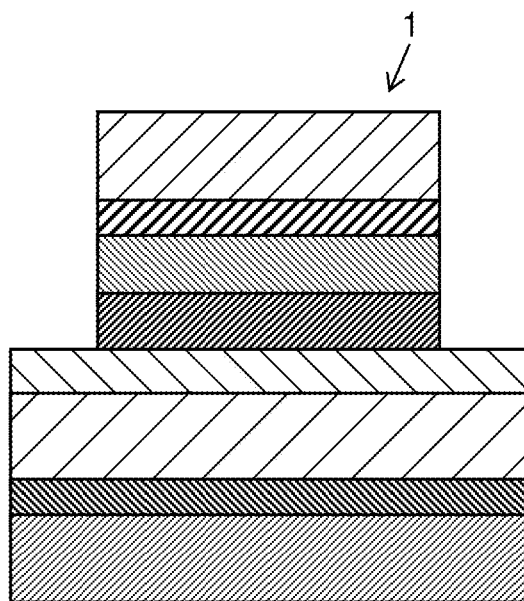


FIG. 9

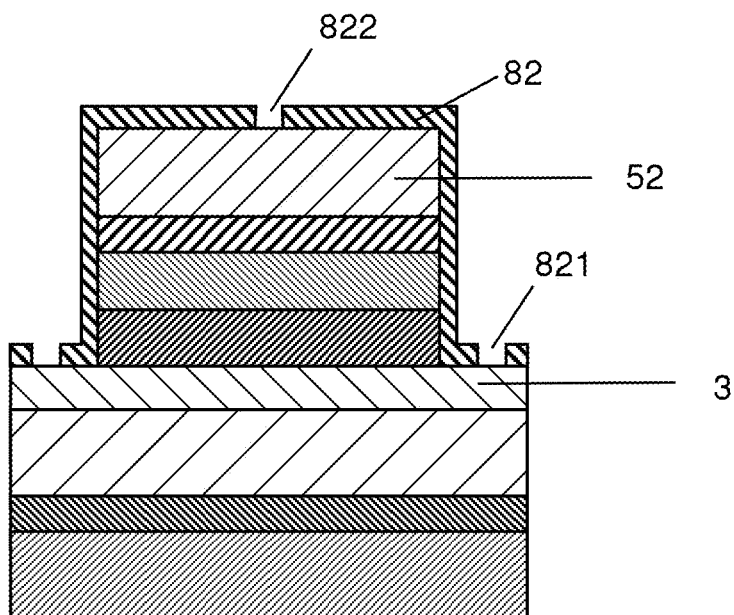


FIG. 10

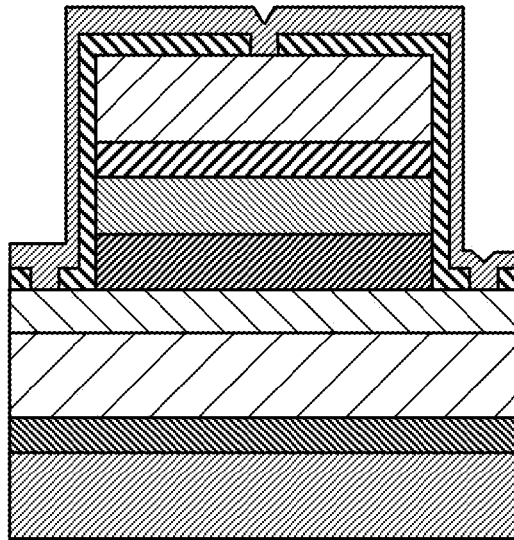


FIG. 11

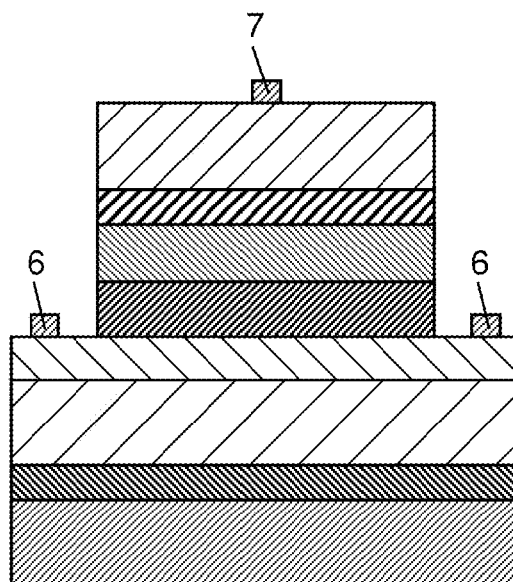




FIG. 12

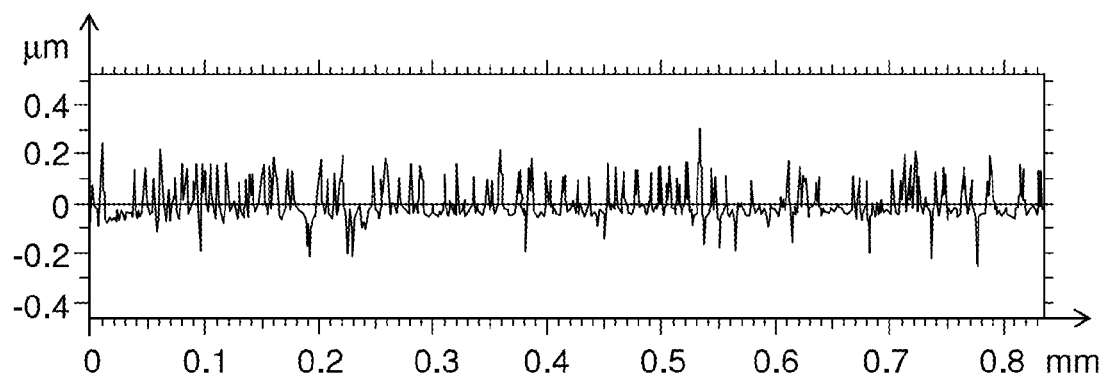


FIG. 13

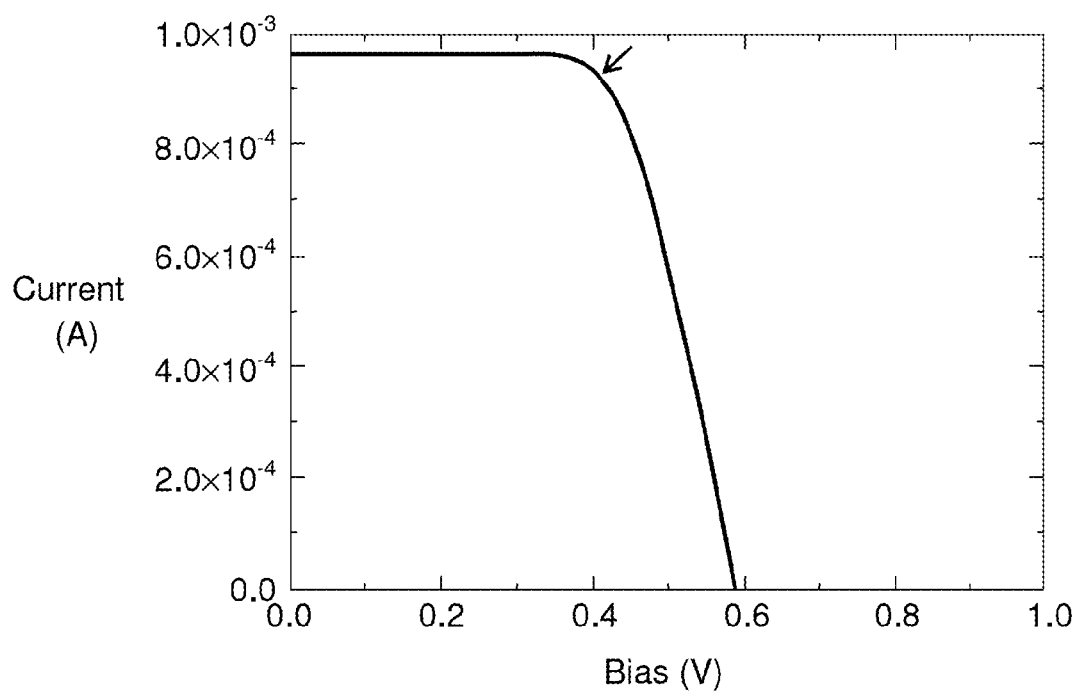


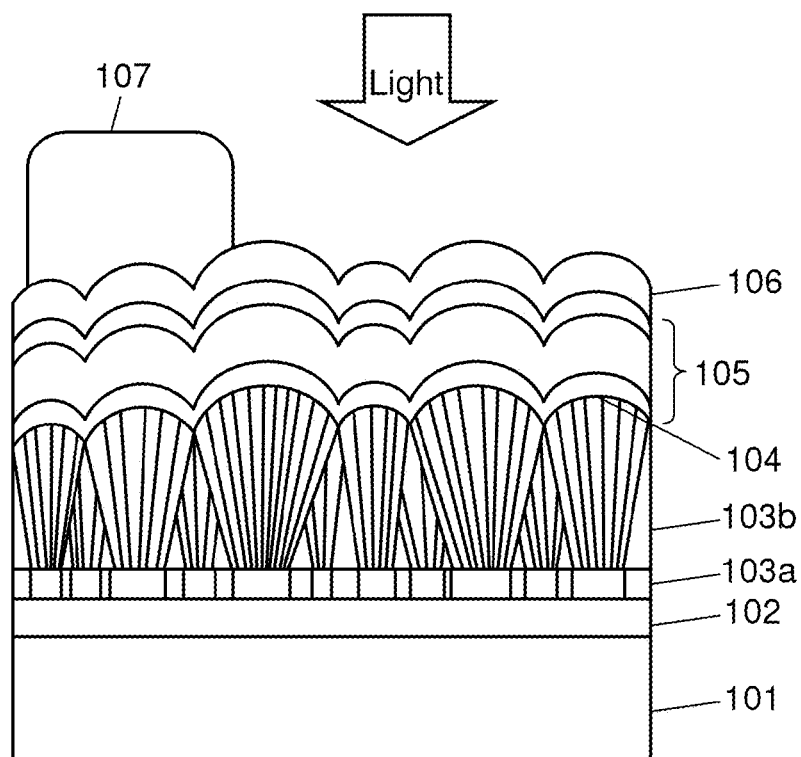
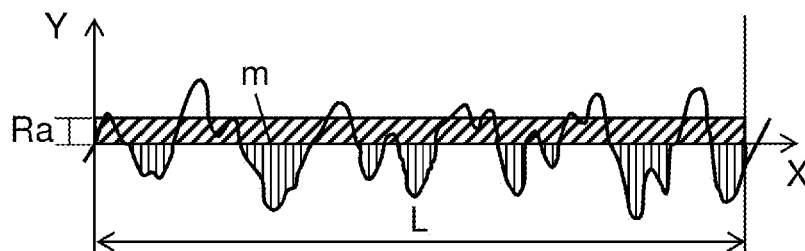
FIG. 14  
PRIOR ART

FIG. 15



$$Ra = \frac{1}{L} \int_0^L |f(x)| dx$$

$L$ =Evaluation Length

FIG. 16

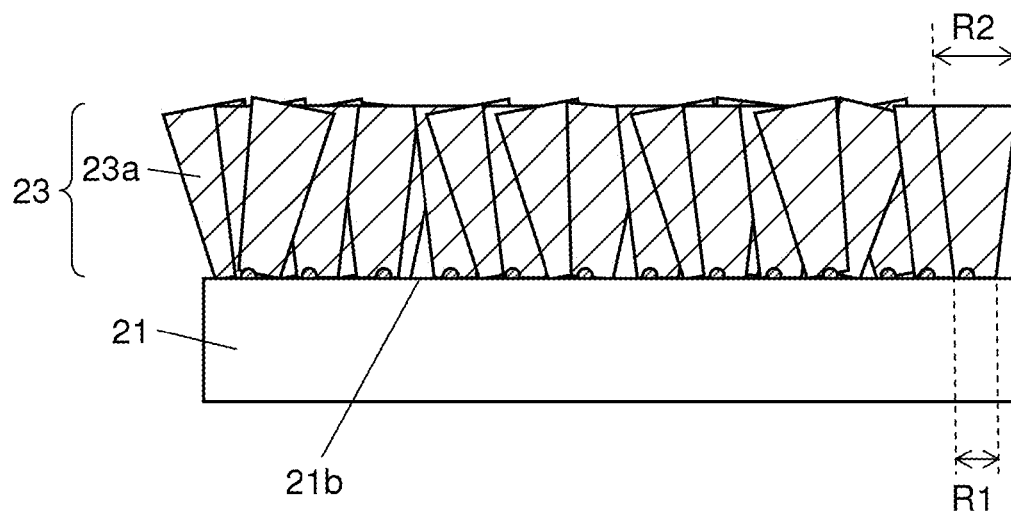
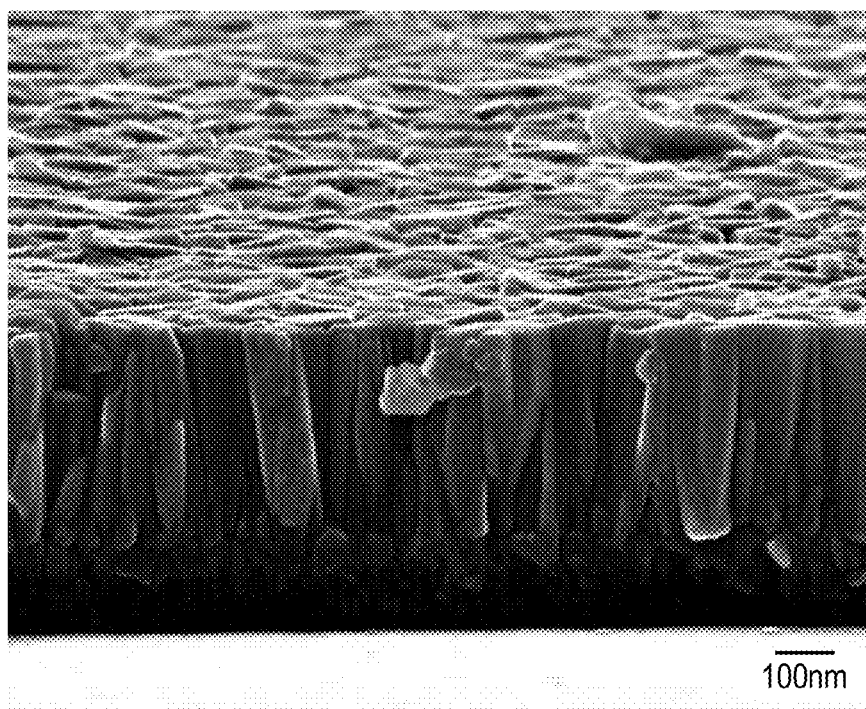


FIG. 17



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# SOLAR CELL ELEMENT AND METHOD FOR MANUFACTURING SAME

This is a continuation of International Application No. PCT/JP2013/001042, with an international filing date of Feb. 25, 2013, which claims priority of Japanese Patent Application No. 2012-083587 filed on Apr. 2, 2012, the contents of which are hereby incorporated by reference.

## TECHNICAL FIELD

The present disclosure relates to a solar cell element and a method for manufacturing the same.

## BACKGROUND ART

FIG. 14 shows a solar cell element disclosed in Patent Literature 1. This solar cell element comprises a substrate 101, a reverse surface reflective layer 102, a first transparent electrode layer 103a formed of ZnO, a second transparent electrode layer 103b formed from ZnO, a semiconductor layer 105, an upper part transparent electrode 106, and a collective electrode 107 in this order.

The second clear electrode layer 103b is composed of a plurality of columnar crystal grains. Each columnar crystal grain has a longitudinal direction along a normal line direction of the substrate 101. The second clear electrode layer 103b has a region where a plurality of columnar crystal grains radiate upwardly.

The upper transparent electrode 106 is irradiated with light from above to generate a voltage difference between the first clear electrode layer 103 and the upper transparent electrode 106.

## CITATION LIST

### Patent Literature

Patent Literature 1: Japanese Patent laid-open Publication No. Hei 11-220154

### Non Patent Literature

Non Patent Literature 1: Jenny Nelson (2003), The physics of Solar Cells, Imperial college press, pp. 11-13.

## SUMMARY OF INVENTION

### Technical Problem

An object of the present disclosure is to provide a novel solar cell element having high photoelectric conversion efficiency.

### Solution to Problem

A1. The present disclosure provides a method for generating an electric power using a solar cell element, the method comprising steps of:

- (a) preparing a solar cell element 9 comprising:
  - a transparent substrate body 21;
  - a  $\text{Na}_x\text{Ag}_{1-x}$  layer 22;
  - a ZnO layer 23;
  - a transparent conductive layer 3;
  - a photoelectric conversion layer 4 including an n-type semiconductor layer 41 and a p-type semiconductor layer 42;
  - an n-side electrode 6; and

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a p-side electrode 7; wherein

the transparent substrate body 21, the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22, the ZnO layer 23, the transparent conductive layer 3, and the photoelectric conversion layer 4 are stacked in this order;

the n-side electrode 6 is electrically connected to the n-type semiconductor layer 41;

the p-side electrode 7 is electrically connected to the p-type semiconductor layer 42;

x represents a value of not less than 0.001 and not more than 0.02;

the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22 has a thickness of not less than 2 nanometers and not more than 15.2 nanometers;

the ZnO layer 23 has an arithmetical mean roughness of not less than 20 nanometers and not more than 750 nanometers;

the ZnO layer 23 is composed of a plurality of ZnO columnar crystal grains 23a grown on the surface of the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22;

each ZnO columnar crystal grain 23a has a longitudinal direction along a line normal to the transparent substrate body 21;

each ZnO columnar crystal grain 23a has a width which increases from the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22 toward the transparent conductive layer 3;

the width of each ZnO columnar crystal grain 23a is perpendicular to the longitudinal direction; and

each ZnO columnar crystal grain 23a has a R2/R1 ratio of not less than 1.1 and not more than 1.6;

where R1 represents a width of a first end of the ZnO columnar crystal grain 23a, the first end being in contact with the surface of the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22; and

R2 represents a width of a second end of the ZnO columnar crystal grain 23a, wherein the second end is opposite the first end; and

(b) irradiating the photoelectric conversion layer 4 with light through the transparent substrate body 21, the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22, the ZnO layer 23, and the transparent conductive layer 3, so as to generate an electric power between the n-side electrode 6 and the p-side electrode 7.

A2. The method for generating an electric power using a solar cell element according to A1, wherein the solar cell element 9 further comprises a reverse surface electrode layer 5; and

the photoelectric conversion layer 4 is interposed between the reverse surface electrode layer 5 and the transparent conductive layer 3.

A3. The method for generating an electric power using a solar cell element according to A2, wherein the n-type semiconductor layer 41 is interposed between the transparent conductive layer 3 and the p-type semiconductor layer 42; and

the p-type semiconductor layer 42 is interposed between the n-type semiconductor layer 41 and the reverse surface electrode layer 5.

A4. The method for generating an electric power using a solar cell element according to A3, wherein the n-side electrode 6 is formed on the transparent conductive layer 3; and the p-side electrode 7 is formed on the reverse surface electrode layer 5.

A5. The method for generating an electric power using a solar cell element according to A1, wherein the ZnO layer 23 has a volume resistivity of not less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

A6. The method for generating an electric power using a solar cell element according to A1, wherein the transparent conductive layer 3 has a volume resistivity of less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

A7. The method for generating an electric power using a solar cell element according to A1, wherein the ZnO layer 23 has a volume resistivity of not less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ ; and

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the transparent conductive layer 3 is formed of ZnO having a volume resistivity of less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

A8. The method for generating an electric power using a solar cell element according to A1, wherein the light is sunlight.

B1. The present disclosure provides a solar cell element 9 comprising:

a transparent substrate body 21;

a  $\text{Na}_x\text{Ag}_{1-x}$  layer 22;

a ZnO layer 23;

a transparent conductive layer 3;

a photoelectric conversion layer 4 including an n-type semiconductor layer 41 and a p-type semiconductor layer 42; an n-side electrode 6; and

a p-side electrode 7; wherein

the transparent substrate body 21, the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22, the ZnO layer 23, the transparent conductive layer 3, and the photoelectric conversion layer 4 are stacked in this order;

the n-side electrode 6 is electrically connected to the n-type semiconductor layer 41;

the p-side electrode 7 is electrically connected to the p-type semiconductor layer 42;

x represents a value of not less than 0.001 and not more than 0.02;

the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22 has a thickness of not less than 2 nanometers and not more than 15.2 nanometers;

the ZnO layer 23 has an arithmetical mean roughness of not less than 20 nanometers and not more than 750 nanometers;

the ZnO layer 23 is composed of a plurality of ZnO columnar crystal grains 23a grown on the surface of the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22;

each ZnO columnar crystal grain 23a has a longitudinal direction along a line normal to the transparent substrate body 21;

each ZnO columnar crystal grain 23a has a width which increases from the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22 toward the transparent conductive layer 3;

the width of each ZnO columnar crystal grain 23a is perpendicular to the longitudinal direction; and

each ZnO columnar crystal grain 23a has a R2/R1 ratio of not less than 1.1 and not more than 1.6;

where R1 represents a width of first end of the ZnO columnar crystal grain 23a, the first end being in contact with the surface of the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22; and

R2 represents a width of a second end of the ZnO columnar crystal grain 23a, wherein the second end is opposite the first end.

B2. The solar cell element according to B1, wherein the solar cell element 9 further comprises a reverse surface electrode layer 5; and

the photoelectric conversion layer 4 is interposed between the reverse surface electrode layer 5 and the transparent conductive layer 3.

B3. The solar cell element according to B2, wherein the n-type semiconductor layer 41 is interposed between the transparent conductive layer 3 and the p-type semiconductor layer 42; and

the p-type semiconductor layer 42 is interposed between the n-type semiconductor layer 41 and the reverse surface electrode layer 5.

B4. The solar cell element according to B3, wherein the n-side electrode 6 is formed on the transparent conductive layer 3; and

the p-side electrode 7 is formed on the reverse surface electrode layer 5.

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B5. The solar cell element according to B1, wherein the ZnO layer 23 has a volume resistivity of not less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

B6. The solar cell element according to B1, wherein the transparent conductive layer 3 has a volume resistivity of less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

B7. The solar cell element according to B1, wherein the ZnO layer 23 has a volume resistivity of not less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ ; and

the transparent conductive layer 3 is formed of ZnO having a volume resistivity of less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

#### Advantageous Effects of Invention

The present disclosure provides a novel solar cell element having high photoelectric conversion efficiency.

#### BRIEF DESCRIPTION OF DRAWINGS

FIG. 1 shows a cross-sectional view of the solar cell element 9 according to the embodiment.

FIG. 2 shows a cross-sectional view of one step included in a method for fabricating the solar cell element 9.

FIG. 3 shows a cross-sectional view of one step subsequent to FIG. 2 included in a method for fabricating the solar cell element 9.

FIG. 4 shows a cross-sectional view of one step subsequent to FIG. 3 included in a method for fabricating the solar cell element 9.

FIG. 5 shows a cross-sectional view of one step subsequent to FIG. 4 included in a method for fabricating the solar cell element 9.

FIG. 6 shows a cross-sectional view of one step subsequent to FIG. 5 included in a method for fabricating the solar cell element 9.

FIG. 7 shows a cross-sectional view of one step subsequent to FIG. 6 included in a method for fabricating the solar cell element 9.

FIG. 8 shows a cross-sectional view of one step subsequent to FIG. 7 included in a method for fabricating the solar cell element 9.

FIG. 9 shows a cross-sectional view of one step subsequent to FIG. 8 included in a method for fabricating the solar cell element 9.

FIG. 10 shows a cross-sectional view of one step subsequent to FIG. 9 included in a method for fabricating the solar cell element 9.

FIG. 11 shows a cross-sectional view of one step subsequent to FIG. 10 included in a method for fabricating the solar cell element 9.

FIG. 12 shows one example of a surface roughness profile.

FIG. 13 shows an I-V-curve obtained in the example 1.

FIG. 14 shows a solar cell element disclosed in Patent Literature 1.

FIG. 15 shows a view for explaining Ra.

FIG. 16 shows an enlarged view of the part surrounded by a dash line A depicted in FIG. 1.

FIG. 17 shows an SEM image of the  $\text{Na}_x\text{Ag}_{1-x}$  layer 22 according to the example 1.

#### DESCRIPTION OF EMBODIMENTS

An embodiment of the present disclosure is described with reference to the drawings.

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## EMBODIMENT

## Step (a)

In the step (a), a solar cell element **9** is prepared.

FIG. 1 shows a cross-sectional view of the solar cell element **9** according to the embodiment.

The solar cell element **9** comprises a transparent substrate **2**, a transparent conductive layer **3**, a photoelectric conversion layer **4**, a reverse surface electrode layer **5**, an n-side electrode **6**, and a p-side electrode **7** in this order.

The transparent substrate **2** includes a transparent substrate body **21**, a  $\text{Na}_x\text{Ag}_{1-x}$  layer **22**, and a ZnO layer **23**. The  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** is interposed between the transparent substrate body **21** and the ZnO layer **23**.

(Transparent Substrate Body **21**)

It is desirable that the transparent substrate body **21** be permeable to light (e.g., sunlight) having a wavelength of not less than 300 nanometers and not more than 1,100 nanometers. Examples of the transparent substrate body **21** include a glass substrate, a ceramics substrate, a plastic substrate, and a metal substrate. In view of the intensity and the heat resistance, a glass substrate having a thickness of from 0.3 millimeters to 7 millimeters is desirable.

( $\text{Na}_x\text{Ag}_{1-x}$  Layer **22**)

The  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** consists of an alloy of sodium and silver. The character of “x” represents a value of not less than 0.001 and not more than 0.02. When the value of x is less than 0.001, the photoelectric conversion efficiency is decreased. See the comparative example 3. Similarly, when the value of x is more than 0.02, the photoelectric conversion efficiency is decreased. See the comparative example 4.

When the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** is not provided, the photoelectric conversion efficiency is decreased. See the comparative example 5.

The  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** has a thickness of not less than 2 nanometers and not more than 15.2 nanometers. Since the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** is significantly thin, the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** is permeable to light. When the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** is not provided, the photoelectric conversion efficiency is decreased. When the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** has a thickness of more than 15.2 nanometers, the photoelectric conversion efficiency is decreased.

The  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** may be formed by a sputtering method.

(ZnO Layer **23**)

The ZnO layer **23** has an arithmetic mean roughness (hereinafter, referred to as “Ra”) of not less than 20 nanometers and not more than 750 nanometers.

The arithmetic mean roughness Ra is the arithmetic mean of the absolute values of distances from the mean line to the surface roughness profile.

The value of Ra is represented by the following formula (I):

[Math 1]

$$Ra = (1/L) \cdot \int_0^L |f(x)| dx \quad (I)$$

where, L: Evaluation length, and f(x): Surface roughness profile.

See FIG. 15.

The value of Ra may be measured with a surface roughness measuring apparatus. The surface roughness measuring apparatus is available from Taylor Hobson Ltd., as trade name “CCI Lite”.

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The surface roughness profile is a profile obtained by measuring the projection-and-recess shape of the surface of an object using a surface roughness measuring apparatus. FIG. 12 shows an example of the surface roughness profile.

When the value of Ra is less than 20 nanometers, the photoelectric conversion efficiency is decreased. See the comparative example 1. When the value of Ra is more than 750 nanometers, the photoelectric conversion efficiency is decreased. See the comparative example 2.

ZnO is transparent. Therefore, the ZnO layer **23** is permeable to light.

As shown in FIG. 16, the ZnO layer **23** is composed of a plurality of ZnO columnar crystal grains **23a**. Each ZnO columnar crystal grain **23a** is grown, using Ag contained in the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** as a core. Na contained in the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** improves the crystallinity of the ZnO columnar crystal grain **23a**.

Each ZnO columnar crystal grain **23a** has a longitudinal direction along a line normal to the transparent substrate body **21**.

Each ZnO columnar crystal grain **23a** has a width which increases from the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** toward the transparent electrode layer **3**. More particularly, each ZnO columnar crystal grain **23a** has a R2/R1 ratio of not less than 1.1 and not more than 1.6. As shown in FIG. 16, the value of R1 represents a width of one end of the ZnO columnar crystal grain **23a**, the one end being in contact with the surface of the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22**. The value of R2 represents a width of the other end of the ZnO columnar crystal grain **23a**, the other end being in contact with the ZnO layer **3**. When the R2/R1 ratio is less than 1.1, the photoelectric conversion efficiency is decreased. See the comparative example 1. When the R2/R1 is more than 1.6, the photoelectric conversion efficiency is decreased. See the comparative example 2.

The width of the ZnO columnar crystal grain **23a** appears by cutting the ZnO columnar crystal grain **23a** along a normal line direction of the transparent substrate body **21**. This width is substantially orthogonal to the longitudinal direction of the ZnO columnar crystal grain **23a**.

The ZnO layer **23** has a volume resistivity of more than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

(Transparent Conductive Layer **3**)

The transparent conductive layer **3** is interposed between the ZnO layer **23** and the photoelectric conversion layer **4**. An example of the material of the transparent conductive layer **3** is zinc oxide doped with at least one selected from the group consisting of gallium, aluminum and boron. The transparent conductive layer **3** has a volume resistivity of less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ . Since the ZnO layer **23** has a great volume resistivity, it is difficult to obtain an electric power from the ZnO layer **23** efficiently. Therefore, it is desirable to provide such a low-resistance transparent conductive layer **3**.

(Photoelectric Conversion Layer **4**)

The photoelectric conversion layer **4** includes an n-type semiconductor layer **41** and a p-type semiconductor layer **42**. Examples of the material of the n-type semiconductor layer **41** include silicon and GaAs. Examples of the material of the p-type semiconductor layer **42** also include silicon and GaAs.

In FIG. 1, the n-type semiconductor layer **41** and the p-type semiconductor layer **42** are formed in this order on the transparent conductive layer **3**. The n-type semiconductor layer **41** is in contact with the p-type semiconductor layer **42** to form a pn-junction.

(Reverse Surface Electrode Layer **5**)

The solar cell element **9** may comprise the reverse surface electrode layer **5**. The reverse surface electrode layer **5** may include a buffer layer **51** and a reflective layer **52**.

The buffer layer **51** is interposed between the photoelectric conversion layer **42** and the reflective layer **52**. Examples of the material of the buffer layer **51** include (a) transparent conductive materials such as zinc oxide, indium oxide, tin oxide, and cadmium oxide, and (b) transparent semiconductor materials such as iron oxide, titanium oxide, zinc selenide, and zinc sulfide. Zinc oxide is desirable.

Examples of the material of the reflective layer **52** include gold, silver, copper, aluminum, platinum, and alloys thereof. Silver is desirable.

#### (n-Side Electrode 6)

The n-side electrode **6** is electrically connected to the n-type semiconductor layer **41**. In FIG. 1, the n-side electrode **6** forms an ohmic contact together with the transparent conductive layer **3**. Examples of a suitable material of the n-side electrode **6** include silver, gold, copper, aluminum, platinum, and alloys thereof. Platinum is desirable.

#### (p-Side Electrode 7)

The p-side electrode **7** is electrically connected to the p-type semiconductor layer **42**. In FIG. 1, the p-side electrode **7** forms an ohmic contact together with the reflective layer **52**. Examples of a suitable material of the p-side electrode **7** include silver, gold, copper, aluminum, platinum, and alloys thereof. Platinum is desirable.

Then, a method for fabricating the solar battery element according to the embodiment is described with reference to FIG. 2-FIG. 11.

First, as shown in FIG. 2, the transparent substrate body **21** is prepared. A glass substrate is desirable. The  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** is formed on the surface of transparent substrate body **21** by a conventional semiconductor growth method such as a RF magnetron sputtering method or a vacuum evaporation method.

Then, the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** is heated. Examples of a heating method include an anneal method, a vacuum heating method, a UV-ozone method, an advanced oxidation process method, an anneal method under oxygen atmosphere, and an anode oxidation method. An anneal method under a temperature of from 50-800 degrees Celsius is desirable. The width of the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** is decreased by the heat treatment. In other words, the area of the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** is decreased. In this way, island-shaped  $\text{Na}_x\text{Ag}_{1-x}$  areas **22** are formed on the transparent substrate body **21**.

Accordingly, the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** may not cover the whole surface of the transparent substrate body **21**. In this case, as shown in FIG. 16, a portion **21b** of the transparent substrate body **21** which is not covered may be exposed. FIG. 16 shows an enlarged view of the part surrounded by the dashed line A depicted in FIG. 1. As shown in FIG. 16, the ZnO layer **23** is composed of the plurality of the ZnO columnar crystal grains **23a**. Since each ZnO columnar crystal grain **23a** has a R2/R1 ratio of not less than 1.1 and not more than 1.6, the upper surface of the ZnO layer **23** does not have an interspace. On the contrary, the portion **21b** of the transparent substrate body **21** which is covered neither by the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** nor by the ZnO layer **23** may be exposed.

The surface roughness of the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** may be varied by the temperature of the heat treatment.

Instead of the above-mentioned formation method of the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22**, the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** may be formed by the following method.

First, a glass substrate containing sodium is prepared as the transparent substrate body **21**. More particularly, a soda-lime glass substrate is prepared. A silver layer is formed on the surface of this transparent substrate body **21**. Subsequently, the transparent substrate body **21** is heated to diffuse the sodium into the silver layer. In this way, the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22**

may be formed. Examples of the heating method include an anneal method and a vacuum-heating method. A vacuum-heating method under a temperature of 200-600 degrees Celsius is desirable.

As shown in FIG. 3, the ZnO layer **23** is formed on the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** by a CBD method using a mixture of  $\text{Zn}(\text{NO}_3)_2$  and hexamethylene tetramine (hereinafter, referred to as "HMT") under a temperature of 20-90 degrees Celsius.

The surface projection-and-recess roughness of the formed ZnO layer **23** become larger with increase of the time of the processing time of the reactive ion etching or the chemical etching. In the reactive ion etching,  $\text{CH}_4$  gas may be used. In the chemical etching, a chloride solution may be used. The ZnO layer **23** is in contact with the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22**. To be more exact, the ZnO layer **23** is in contact with the top surface of the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22**.

As shown in FIG. 4, the transparent conductive layer **3** is formed on the ZnO layer **23** uniformly. An example of the method for forming the transparent conductive layer **3** is a pulse laser deposition method (hereinafter, referred to as "PLD method").

As shown in FIG. 5, the n-type silicon layer **41** and the p-type silicon layer **42** are deposited in this order on the transparent conductive layer **3** by a plasma CVD method to form the photoelectric conversion layer **4**.

The n-type silicon layer **41** may be formed by a plasma CVD method using a gaseous mixture containing phosphine, silane, and hydrogen. The p-type silicon layer **41** is deposited by a plasma CVD method using a gaseous mixture containing diborane, silane, methane, and hydrogen.

As shown in FIG. 6, the reverse surface electrode layer **5** including a buffer layer **51** and a reflective layer **52** is formed.

Examples of a method for forming the buffer layer **51** include a PLD method, a RF magnetron sputtering method, and a vacuum evaporation method.

Examples of a method for forming the reflective layer **52** include a RF magnetron sputtering method and a vacuum evaporation method.

In this way, a laminate **1** shown in FIG. 6 is obtained.

Then, as shown in FIG. 7, a first mask **81** is formed on the surface of the laminate **1** by photolithography.

As shown in FIG. 8, an unnecessary portion of the laminate **1** is removed by etching. More particularly, an unnecessary portion of the reflective layer **52** and an unnecessary portion of the buffer layer **51** are removed by wet-etching using with a mixture solution of hydrochloric acid and nitric acid. Furthermore, an unnecessary portion of the photoelectric conversion layer **4** is removed by ICP plasma etching using a gaseous mixture of oxygen, argon, and  $\text{SF}_6$ , using this resist film as the first mask **81**.

Finally, the first mask **81** is removed.

As shown in FIG. 9, a second mask **82** is formed by photolithography. This second mask **82** has a first opening **821** and a second opening **822**. The transparent conductive layer **3** is located under the first opening **821**. The reflective layer **52** is located under the second opening **822**.

As shown in FIG. 10, a metal layer is formed on the second mask **82** by a sputter vacuum deposition method or an electron beam evaporation method. Finally, the second mask **82** is removed, as shown in FIG. 11. In this way, the n-side electrode **6** and the p-side electrode **7** are formed.

#### Step (b)

In the step (b), as shown in FIG. 1, the transparent substrate body **21** is irradiated with light. The light penetrates the transparent substrate body **21**, the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22**, the ZnO

layer **23**, and the transparent conductive layer **3** to reach the photoelectric conversion layer **4**. The light is converted into electricity by the photoelectric conversion layer **4**. In this way, an electric power is generated between the n-side electrode **6** and the p-side electrode **7**.

### EXAMPLES

The following examples describe the present disclosure in more detail.

#### Example 1

In the example 1, the solar cell element **9** shown in FIG. 1 was fabricated in accordance with the method shown in FIG. 2-FIG. 11.

First, a glass substrate having a thickness of 5 millimeters was prepared as the transparent substrate body **21**. The transparent substrate body **21** had a length of 25 millimeters and a width of 25 millimeters. The transparent substrate body **21** had a light transmittance of 88-90%. The transparent substrate body **21** was immersed in ethanol and washed under an ultrasonic application.

Then, the  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** ( $x=0.001$ ) was formed on the transparent substrate body **21** by a RF magnetron sputtering method. In the RF magnetron sputtering method, used was a mixture target of Na and Ag having a molar ratio of 1:999. The formed  $\text{Na}_x\text{Ag}_{1-x}$  layer **22** had a thickness of 2 nanometers.

The transparent substrate body **21** thus provided was heated under a temperature of 400 degrees Celsius for ten minutes.

Then, as shown in FIG. 3, the transparent substrate body **21** was immersed in a liquid mixture of  $\text{Zn}(\text{NO}_3)_2$  and HMT warmed at 70 degrees Celsius for three hours so as to form the ZnO layer **23**. The  $\text{Zn}(\text{NO}_3)_2$  had a concentration of 0.1M. The HMT also had a concentration of 0.1M. The formed ZnO layer **23** had a thickness of 1 micrometer.

The Ra of the formed ZnO layer **23** was measured with a surface roughness measuring apparatus (available from Taylor Hobson Ltd., trade name "CCI Lite"). As a result, the value of Ra was 22 nanometers.

Then, the values of R1 and R2 of the ZnO columnar crystal grain **23a** contained in the ZnO layer **23** were measured. More particularly, the laminate **1** was cut along a normal line direction of the transparent substrate body **21**. Subsequently, a SEM image of the cross-section thus appeared was obtained. FIG. 17 shows a SEM image of the ZnO layer **23** included in the laminate **1** which was thus cut. On the basis of the SEM image, the values of R1 and R2 were measured.

As a result, the value of R1 was 115 nanometers. The value of R2 was 149 nanometers. Therefore, the R2/R1 ratio was approximately 1.3.

A volume resistivity was calculated on the basis of the following formula:

$$\text{Volume resistivity} = RE \cdot t \cdot RCF$$

Here, the value of RE represents a resistance value measured according to a four-terminal measurement method. A measurement apparatus for measuring a resistance value measured according to the four-terminal measurement method is available from Mitsubishi Chemical Corporation, as a trade name: Loresta-Gp MCP-T610.

The value of t represents a thickness of the ZnO layer **23**.

The value of RCF represents a resistivity correction factor. In this example, the value of RCF was 4.398.

As a result, the ZnO layer **23** had a volume resistivity of  $9.96 \times 10^{-3} \Omega \cdot \text{cm}$ .

Then, as shown in FIG. 4, the transparent conductive layer **3** was formed on the ZnO layer **23** by a PLD method. The material of the transparent conductive layer **3** was zinc oxide where 5.7 weight % of gallium was doped. Hereinafter, zinc oxide doped with gallium is referred to as "GZO". The transparent conductive layer **3** had a thickness of 100 nanometers. The volume resistivity of the transparent conductive layer **3** was measured similarly to that of the ZnO layer **23**. As a result, the transparent conductive layer **3** had a volume resistivity of  $5.2 \times 10^{-4} \Omega \cdot \text{cm}$ .

As shown in FIG. 5, the n-type semiconductor layer **41** consisting of n-type silicon and the p-type semiconductor layer **42** consisting of p-type silicon were formed in this order by a plasma CVD method so as to form the photoelectric conversion layer **4**. The n-type semiconductor layer **41** had a thickness of 40 nanometers. The p-type semiconductor layer **42** had a thickness of 11 nanometers.

As shown in FIG. 6, a GZO film having a thickness of 40 nanometers was formed on the p-type semiconductor layer **42** by a sputter vacuum deposition method. In this way, the buffer layer **51** consisting of the GZO film was formed.

Furthermore, a silver layer having a thickness of 200 nanometers was formed on the buffer layer **51** by a sputter vacuum deposition method. In this way, the reflective layer **52** consisting of silver was formed.

As shown in FIG. 7, the resist film **81** of 20 millimeters square was formed on the reflective layer **52** by photolithography. Using this resist film as the first mask **81**, an unnecessary portion of the reflective layer **52** and an unnecessary portion of the buffer layer **51** were removed by wet-etching using a liquid mixture of hydrochloric acid and nitric acid. Furthermore, using this resist film as the first mask **81**, an unnecessary portion of the photoelectric conversion layer **4** was removed by ICP plasma etching using a gaseous mixture of oxygen, argon, and  $\text{SF}_6$ .

Subsequently, as shown in FIG. 8, the first mask **81** was removed.

As shown in FIG. 9, the second mask **82** was formed by photolithography. The second mask **82** had a first opening **821** and a second opening **822**. The first opening **821** was formed on the transparent conductive layer **3**. The first opening **821** had a size of 22 millimeters square. The second opening **822** was formed on the reflective layer **52**. The second opening **822** had a size of 2 micrometers  $\times$  22 millimeters.

As shown in FIG. 10, a platinum film having a thickness of 100 nanometers was formed so that the second mask was covered with the platinum film.

Finally, as shown in FIG. 11, the resist film **82** was removed to form the n-side electrode **6** consisting of platinum and the p-side electrode **7** consisting of platinum. In this way, the solar cell element **9** was provided.

During the measurement of the photoelectric conversion efficiency, the transparent substrate body **21** was irradiated with pseudo-sunlight which is described later.

The photoelectric conversion efficiency of the solar cell element **9** was calculated as below.

The transparent substrate body **21** was irradiated with the pseudo-sunlight having a power energy of 100 mW/cm<sup>2</sup>.

The pseudo-sunlight was radiated from a lamp that is a combination of a xenon lamp (available from Wacom Electric Co., Ltd.) of 500 watts and a halogen lamp (available from Wacom Electric Co., Ltd.) of 400 watts.

The open circuit voltage  $V_{oc}$  when the n-side electrode **6** and the p-side electrode **7** were electrically opened was measured.

The short-circuit current  $I_{sc}$  when the n-side electrode **6** and the p-side electrode **7** were short-circuited was measured.



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An I-V curve as shown in FIG. 13 was obtained using a solar simulator (available from Wacom Electric Co., Ltd., Trade name: Super Solar simulator WXS-90S-L2).

On the basis of FIG. 13, the fill factor (hereinafter, referred to as "FF") was obtained in accordance with the disclosure of Non Patent Literature 1.

[Non Patent Literature 1] Jenny Nelson (2003), The physics of Solar Cells, Imperial college press, pp. 11-13.

The fill factor FF is calculated in accordance with the following math formula.

$$FF = \frac{V_{max} \cdot I_{max}}{V_{oc} \cdot I_{sc}} \quad [\text{Math 2}]$$

In the formula, Vmax means the voltage when the V·I value of the I-V curve is maximum in FIG. 13 (See the arrow in FIG. 13).

I<sub>max</sub> means the electric current when the V·I value of the I-V curve is maximum in FIG. 13 (See the arrow in FIG. 13).

The photoelectric conversion efficiency is calculated in accordance with the following formula.

$$\text{Photoelectric conversion efficiency} = V_{oc} \cdot I_{sc} \cdot FF$$

In the formula,

$$J_{sc} = I_{sc} / S$$

S (effective light-receiving surface area)=400 square micrometers

The results are shown in Table 1.

## Example 2

An experiment similar to the example 1 was conducted, except that the Na<sub>0.001</sub>Zn<sub>0.999</sub> layer had a thickness of 15.2 nanometers. The results are shown in Table 1.

## Example 3

An experiment similar to the example 1 was conducted, except that the ZnO layer 23 was formed with a liquid mixture of 0.05M Zn (NO<sub>3</sub>)<sub>2</sub> and 0.05M HMT. The results are shown in Table 1.

## Example 4

An experiment similar to the example 1 was conducted, except that the ZnO layer 23 was formed with a liquid mixture of 0.75M Zn (NO<sub>3</sub>)<sub>2</sub> and 0.75M HMT. The results are shown in Table 1.

## Example 5

An experiment similar to the example 1 was conducted, except that x=0.02. The results are shown in Table 1.

## Comparative Example 1

An experiment similar to the example 1 was conducted, except that the ZnO layer 23 was formed with a liquid mixture of 0.01M Zn (NO<sub>3</sub>)<sub>2</sub> and 0.01M HMT. The results are shown in Table 2.

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## Comparative Example 2

An experiment similar to the example 1 was conducted, except that the ZnO layer 23 was formed with a liquid mixture of 1M Zn (NO<sub>3</sub>)<sub>2</sub> and 1M HMT. The results are shown in Table 2.

## Comparative Example 3

An experiment similar to the example 1 was conducted, except that x=0.0005. The results are shown in Table 2.

## Comparative Example 4

An experiment similar to the example 1 was conducted, except that x=0.05. The results are shown in Table 2.

## Comparative Example 5

An experiment similar to the example 1 was conducted, except that the Na<sub>x</sub>Ag<sub>1-x</sub> layer 22 was not formed. The results are shown in Table 2.

## Comparative Example 6

An experiment similar to the example 1 was conducted, except that the Na<sub>0.001</sub>Ag<sub>0.999</sub> layer 22 had a thickness of 42.1 nanometers. The results are shown in Table 3.

## Comparative Example 7

An experiment similar to the example 1 was conducted, except that ZnO nanoparticles having an average particle diameter (d50) of 2.2 nanometers were applied on the transparent substrate body 21 by a spin-coater method, instead of the Na<sub>x</sub>Ag<sub>1-x</sub> layer 22. The formed layer had a thickness of 2.2 nanometers. The ZnO nanoparticles were synthesized by a sol-gel method. The results are shown in Table 3.

TABLE 1

	Example 1	Example 2	Example 3	Example 4	Example 5
Value of x	0.001	0.001	0.001	0.001	0.02
Thickness of Na <sub>x</sub> Ag <sub>1-x</sub> layer 22	2.0 nm	15.2 nm	2.0 nm	2.0 nm	2.0 nm
Zn(NO <sub>3</sub> ) <sub>2</sub> concentration	0.1M	0.1M	0.05M	0.75M	0.1M
HMT concentration	0.1M	0.1M	0.05M	0.75M	0.1M
R2 (unit: nanometer)	149	169	108	358	198
R1 (unit: nanometer)	115	121	98	224	132
R2/R1 ratio	1.3	1.4	1.1	1.6	1.5
Ra (unit: nanometer)	2.2	489	19	723	56
Photoelectric conversion efficiency	9.5%	9.7%	9.1%	8.9%	9.7%

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TABLE 2

	Com- parative exam- ple 1	Com- parative example 2	Com- parative example 3	Com- parative example 4	Com- parative example 5
Value of x	0.001	0.001	0.0005	0.05	—
Thickness of Na <sub>x</sub> Ag <sub>1-x</sub> layer	2.0 nm	2.0 nm	2.1 nm	2.0 nm	—
Zn(NO <sub>3</sub> ) <sub>2</sub> concentration	0.01M	1M	0.1M	0.1M	0.1M
HMT concentration	0.01M	1M	0.1M	0.1M	0.1M
R2 (unit: Nanometer)	97	384	112	196	—
R1 (unit: Nanometer)	92	197	86	109	—
R2/R1 ratio	1.05	1.95	1.3	1.8	—
Ra (unit: Nanometer)	10	1879	26	31	—
Photoelectric conversion efficiency	7.4%	6.8%	7.6%	7.2%	7.7%

TABLE 3

	Comparative example 6	Comparative example 7
Value of x	0.001	—
Thickness of Na <sub>x</sub> Ag <sub>1-x</sub> layer	42.1 nm	—
Zn(NO <sub>3</sub> ) <sub>2</sub> concentration	0.1M	0.1M
HMT concentration	0.1M	0.1M
R2 (unit: nanometer)	172	150
R1 (unit: nanometer)	132	125
R2/R1 ratio	1.3	1.2
Ra (unit: nanometer)	856	428
Photoelectric conversion efficiency	7.0%	7.1%

As is clear from Table 1, Table 2, and Table 3, if all of the following requirements (A) to (D) are satisfied, the solar cell element **9** has high photoelectric conversion efficiency.

Requirement (A): The value of x is not less than 0.001 and not more than 0.02. See the comparative example 3 and the comparative example 4.

Requirement (B): The Na<sub>x</sub>Ag<sub>1-x</sub> layer **22** has a thickness of not less than 2 nanometers and not more than 15.2 nanometers. See the comparative example 6.

Requirement (C): The ZnO layer **23** has a value of Ra of not less than 20 nanometers and not more than 750 nanometers. See the comparative example 1 and comparative example 2.

Requirement (D): The R2/R1 ratio falls within a range of not less than 1.1 and not more than 1.6. See the comparative example 1, the comparative example 2 and the comparative example 4.

#### INDUSTRIAL APPLICABILITY

The present disclosure provides a solar cell element having high photoelectric conversion efficiency.

#### REFERENCE SIGNS LIST

- 1: laminate
- 2: transparent substrate
  - 21: transparent substrate body
  - 22: Na<sub>x</sub>Ag<sub>1-x</sub> layer
  - 23: ZnO layer

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- 3: transparent conductive layer
- 4: photoelectric conversion layer
- 41: n-type semiconductor layer
- 42: p-type semiconductor layer
- 5: reverse surface electrode layer
- 51: buffer layer
- 52: reflective layer
- 6: n-side electrode
- 7: p-side electrode
- 81: first mask
- 82: second mask
- 821: first opening
- 822: second opening
- 9: solar cell element

The invention claimed is:

1. A method for generating an electric power using a solar cell element, the method comprising steps of:

(a) preparing a solar cell element comprising:

- a transparent substrate body;
  - a Na<sub>x</sub>Ag<sub>1-x</sub> layer;
  - a ZnO layer;
  - a transparent conductive layer;
  - a photoelectric conversion layer including an n-type semiconductor layer and a p-type semiconductor layer;
  - an n-side electrode; and
  - a p-side electrode; wherein
- the transparent substrate body, the Na<sub>x</sub>Ag<sub>1-x</sub> layer **22**, the ZnO layer, the transparent conductive layer, and the photoelectric conversion layer are stacked in this order; the n-side electrode is electrically connected to the n-type semiconductor layer; the p-side electrode is electrically connected to the p-type semiconductor layer;

x represents a value of not less than 0.001 and not more than 0.02;

the Na<sub>x</sub>Ag<sub>1-x</sub> layer has a thickness of not less than 2 nanometers and not more than 15.2 nanometers;

the ZnO layer has an arithmetic mean roughness of not less than 20 nanometers and not more than 750 nanometers;

the ZnO layer is composed of a plurality of ZnO columnar crystal grains grown on the surface of the Na<sub>x</sub>Ag<sub>1-x</sub> layer;

each ZnO columnar crystal grain has a longitudinal direction along a line normal to the transparent substrate body;

each ZnO columnar crystal grain has a width which increases from the Na<sub>x</sub>Ag<sub>1-x</sub> layer toward the transparent conductive layer;

the width of each ZnO columnar crystal grain is perpendicular to the longitudinal direction; and

each ZnO columnar crystal grain has a R2/R1 ratio of not less than 1.1 and not more than 1.6;

where R1 represents a width of a first end of the ZnO columnar crystal grain, the first end being in contact with the surface of the Na<sub>x</sub>Ag<sub>1-x</sub> layer; and

R2 represents a width of a second end of the ZnO columnar crystal grain, wherein the second end is opposite to the first end; and

(b) irradiating the photoelectric conversion layer with light through the transparent substrate body, the Na<sub>x</sub>Ag<sub>1-x</sub> layer, the ZnO layer, and the transparent conductive layer, so as to generate electric power between the n-side electrode and the p-side electrode.

2. The method according to claim 1, wherein the solar cell element further comprises a reverse surface electrode layer; and

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the photoelectric conversion layer is interposed between the reverse surface electrode layer and the transparent conductive layer.

3. The method according to claim 2, wherein the n-type semiconductor layer is interposed between the transparent conductive layer and the p-type semiconductor layer; and

the p-type semiconductor layer is interposed between the n-type semiconductor layer and the reverse surface electrode layer.

4. The method according to claim 3, wherein the n-side electrode is formed on the transparent conductive layer; and

the p-side electrode is formed on the reverse surface electrode layer.

5. The method according to claim 1, wherein the ZnO layer has a volume resistivity of not less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

6. The method according to claim 1, wherein the transparent conductive layer has a volume resistivity of less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

7. The method according to claim 1, wherein the ZnO layer has a volume resistivity of not less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ ; and

the transparent conductive layer is formed of ZnO having a volume resistivity of less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

8. The method according to claim 1, wherein the light is sunlight.

9. A solar cell element comprising:

a transparent substrate body;

a  $\text{Na}_x\text{Ag}_{1-x}$  layer;

a ZnO layer;

a transparent conductive layer;

a photoelectric conversion layer including an n-type semiconductor layer and a p-type semiconductor layer;

an n-side electrode; and

a p-side electrode; wherein

the transparent substrate body, the  $\text{Na}_x\text{Ag}_{1-x}$  layer, the ZnO layer, the transparent conductive layer, and the photoelectric conversion layer are stacked in this order;

the n-side electrode is electrically connected to the n-type semiconductor layer;

the p-side electrode is electrically connected to the p-type semiconductor layer;

x represents a value of not less than 0.001 and not more than 0.02;

the  $\text{Na}_x\text{Ag}_{1-x}$  layer has a thickness of not less than 2 nanometers and not more than 15.2 nanometers;

the ZnO layer has an arithmetic mean roughness of not less than 20 nanometers and not more than 750 nanometers;

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the ZnO layer is composed of a plurality of ZnO columnar crystal grains grown on the surface of the  $\text{Na}_x\text{Ag}_{1-x}$  layer;

each ZnO columnar crystal grain has a longitudinal direction along a line normal to the transparent substrate body;

each ZnO columnar crystal grain has a width which increases from the  $\text{Na}_x\text{Ag}_{1-x}$  layer toward the transparent conductive layer;

the width of each ZnO columnar crystal grain is perpendicular to the longitudinal direction; and

each ZnO columnar crystal grain has a R2/R1 ratio of not less than 1.1 and not more than 1.6;

where R1 represents a width of a first end of the ZnO columnar crystal grain, the first end being in contact with the surface of the  $\text{Na}_x\text{Ag}_{1-x}$  layer; and

R2 represents a width of a second end of the ZnO columnar crystal grain, wherein the second end is opposite to the first end.

10. The solar cell element according to claim 9, wherein the solar cell element further comprises a reverse surface electrode layer; and

the photoelectric conversion layer is interposed between the reverse surface electrode layer and the transparent conductive layer.

11. The solar cell element according to claim 10, wherein the n-type semiconductor layer is interposed between the transparent conductive layer and the p-type semiconductor layer; and

the p-type semiconductor layer is interposed between the n-type semiconductor layer and the reverse surface electrode layer.

12. The solar cell element according to claim 11, wherein the n-side electrode is formed on the transparent conductive layer; and

the p-side electrode is formed on the reverse surface electrode layer.

13. The solar cell element according to claim 9, wherein the ZnO layer has a volume resistivity of not less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

14. The solar cell element according to claim 9, wherein the transparent conductive layer has a volume resistivity of less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

15. The solar cell element according to claim 9, wherein the ZnO layer has a volume resistivity of not less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ ; and

the transparent conductive layer is formed of ZnO having a volume resistivity of less than  $1 \times 10^{-3} \Omega \cdot \text{cm}$ .

\* \* \* \* \*